

FCC
EMC
TEST REPORT

ISSUED BY
Shenzhen BALUN Technology Co., Ltd.



FOR
Share Stick

ISSUED TO
Trend Power Limited

Flat 1, 3/F, Kwai Cheong Ctr, 40-52 Kwai Cheong Rd, Kwai Chung, N.T.,
HK



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Date: *Nov 17, 2014*

Approved by: *Wei Yanguan*

Wei Yanguan
(Chief Engineer)

Date: *Nov 17, 2014*

Report No.: BL-SZ14A0118-401

EUT Type: Share Stick

Model Name: SHARESTICK-1402-01Y,
SHARESTICK-1402-01B,
SHARESTICK-1402-01G,
SHARESTICK-1402-01O,
SHARESTICK-1402-01P

Brand Name: Power Trend

Test Standard: 47 CFR Part 15 Subpart B

FCC ID: SZJ-SHARESTICK01

Test conclusion: PASS

Test Date: Oct 25, 2014 ~ Nov 15, 2014

Date of Issue: Nov 17, 2014

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Revision History

Version	Issue Date	Revisions
<u>Rev. 01</u>	<u>Nov 17, 2014</u>	<u>Initial Issue</u>

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1 GENERAL INFORMATION

A.1 Identification of the Testing Laboratory

Company Name	Shenzhen BALUN Technology Co., Ltd.
Address	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Phone Number	+86 755 6683 3402
Fax Number	+86 755 6182 4271

A.2 Identification of the Responsible Testing Location

Test Location	Shenzhen BALUN Technology Co., Ltd.
Address	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Accreditation Certificate	The laboratory has been listed by Industry Canada to perform electromagnetic emission measurements. The recognition numbers of test site are 11524A-1. The laboratory has been listed by US Federal Communications Commission to perform electromagnetic emission measurements. The recognition numbers of test site are 832625. The laboratory has met the requirements of the IAS Accreditation Criteria for Testing Laboratories (AC89), has demonstrated compliance with ISO/IEC Standard 17025:2005. The accreditation certificate number is TL-588. The laboratory is a testing organization accredited by China National Accreditation Service for Conformity Assessment (CNAS) according to ISO/IEC 17025. The accreditation certificate number is L6791.
Description	All measurement facilities used to collect the measurement data are located at Block B, FL 1, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China 518055

A.3 Test Environment Condition

Ambient Temperature	23 to 26°C
Ambient Relative Humidity	45 to 55%
Ambient Pressure	90 to 92 kPa

A.4 Announce

- (1) The test report is invalid if not marked with the signatures of the persons responsible for preparing and approving the test report.
- (2) The test report is invalid if there is any evidence and/or falsification.
- (3) The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein.
- (4) This document may not be altered or revised in any way unless done so by BALUN and all revisions are duly noted in the revisions section.
- (5) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.

2 PRODUCT INFORMATION

A.5 Applicant

Applicant	Trend Power Limited
Address	Flat 1, 3/F, Kwai Cheong Ctr, 40-52 Kwai Cheong Rd, Kwai Chung, N.T., HK

A.6 Manufacturer

Manufacturer	Trend Power Limited
Address	Flat 1, 3/F, Kwai Cheong Ctr, 40-52 Kwai Cheong Rd, Kwai Chung, N.T., HK

A.7 General Description for Equipment under Test (EUT)

EUT Type	Share Stick
The Under Test Model Name	SHARESTICK-1402-01Y
Series Model Name	SHARESTICK-1402-01B, SHARESTICK-1402-01G, SHARESTICK-1402-01O, SHARESTICK-1402-01P, SHARESTICK-1402-01Y
Description of Model Name Differentiation	The equipment model SHARESTICK-1402-01Y and SHARESTICK-1402-01B, SHARESTICK-1402-01G, SHARESTICK-1402-01O, SHARESTICK-1402-01P are the Share Stick model, the electrical parameters and internal structure of circuit are same, only the color is different.
Hardware Version	V0.4
Software Version	V1402.112
About the Product	The EUT is the Share Stick, it contains WIFI Module operating at 2.4GHz ISM band which supports 802.11b, 802.11g and 802.11n (HT20/40).

Note: The above EUT information in section 2.3 was declared by manufacturer and for more detailed features description, please refer to the manufacturer's specifications or user's manual.

A.8 Ancillary Equipment

Ancillary Equipment	Battery	
	Brand Name	N/A
	Model No	753668
	Serial No	(N/A. marked #1 by test site)
	Capacitance	5200mAh
	Rated Voltage	3.7V
	Charge Limit	4.2V
	Extreme Voltage	Low: 3.5V / High:4.2V

3 SUMMARY OF TEST RESULTS

A.9 Test Standards

No.	Identity	Document Title
1	FCC 47 CFR Part 15 Subpart B (10-1-09 Edition)	Unintentional Radiators
2	ANSI C63.4-2014	American National Standard for Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz

A.10 Verdict

No.	Description	FCC Rule	Test Verdict	Result
1	Radiated Emission	15.109	PASS	Annex A .1
2	Conducted Emission, AC Ports(PC port)	15.107	PASS	Annex A .2

Note: The EUT only by the USB port power supply. The Conducted Emission at AC Port (EUT connected to a laptop during the test) is tested in this report.

A.11 Test Uncertainty

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of $k=2$.

Measurement	Value
Radiated emissions (30MHz-1GHz)	2.11 dB
Radiated emissions (1GHz-18GHz)	3.31 dB
Conducted emissions (9KHz-30MHz)	1.12 dB

4 GENERAL TEST CONFIGURATIONS

A.12 Test Environments

Environment Parameter	Selected Values During Tests		
	Temperature	Voltage	Relative Humidity
Normal Temperature, Normal Voltage (NTNV)	23°C~25°C	DC 5V	50%-55%

A.13 Test Equipment List

Radiated Emission Test						
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	ROHDE&SCHWARZ	ESRP	101036	2014.07.07	2015.07.06	☒
Test Antenna- Loop(9kHz- 30MHz)	SCHWARZBECK	FMZB 1519	1519-037	2013.07.02	2015.07.01	☐
Test Antenna- Bi-Log(30MHz -3GHz)	SCHWARZBECK	VULB 9163	9163-624	2013.07.03	2015.07.02	☒
Test Antenna- Horn(1- 18GHz)	SCHWARZBECK	BBHA 9120D	9120D-1148	2013.07.02	2015.07.01	☒
Test Antenna- Horn(15- 26.5GHz)	SCHWARZBECK	BBHA 9170	9170-305	2013.07.02	2015.07.01	☐
Anechoic Chamber	RAINFORD	9m*6m*6 m	N/A	2014.10.07	2015.10.06	☒

Conducted disturbance Test						
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	ROHDE&SCHWARZ	ESRP	101036	2014.07.07	2015.07.06	☒
LISN	SCHWARZBECK	NSLK 8127	8127-687	2014.07.07	2015.07.06	☒
AMN	SCHWARZBECK	NNBM812 4	8124-509	2014.07.07	2015.07.06	☐
AMN	SCHWARZBECK	NNBM812 4	8124-510	2014.07.07	2015.07.06	☐
ISN	TESEQ	ISN T800	34449	2014.07.07	2015.07.06	☐

A.14 Test Enclosure list

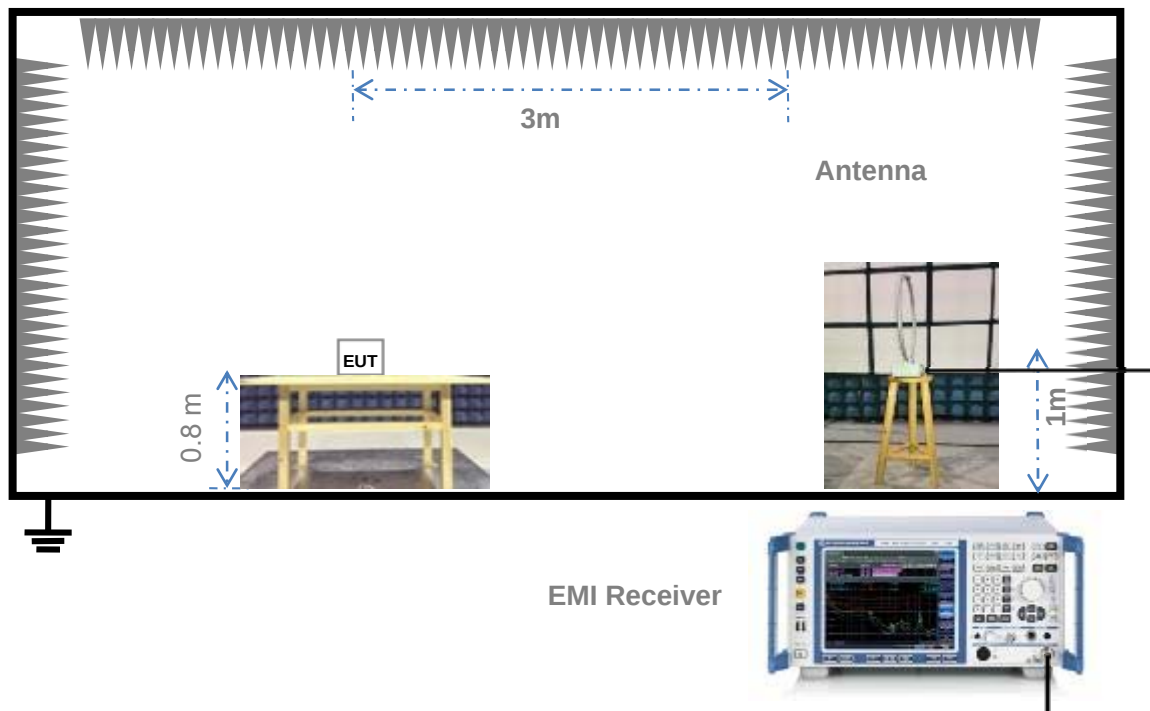
Description	Manufacturer	Model	Serial No.	Length	Description	Use
PC	N/A	N/A	N/A	N/A	Special Handled	☐
Printer	HP	DESKJET 1000	N/A	N/A	N/A	☐
Keyboard	Logitech	Y-BP62a	N/A	N/A	N/A	☐
Mouse	Logitech	M100	N/A	N/A	N/A	☐
USB disk	Kingston	N/A	N/A	N/A	N/A	☐
TF Card	Kingston	N/A	N/A	N/A	N/A	☐
SD Card	Kingston	N/A	N/A	N/A	N/A	☒
Phone	BBK	HCD007TSD	N/A	N/A	N/A	☐
laptop	LENOVO	K29	N/A	N/A	N/A	☒
Artificial load	N/A	N/A	N/A	N/A	10 Ω/100W	☒
RJ45 Cable	N/A	N/A	N/A	1.5m	N/A	☐
USB Cable	N/A	N/A	N/A	1.0m	N/A	☒
Electronic Load	N/A	N/A	N/A	N/A	N/A	☐

A.15 Test Configurations

Test Configurations (TC) No.	Description
TC01	<u>The USB Test mode</u> The EUT configuration of the emission tests is EUT + USB Cable + laptop. During the measurement, the EUT is connected with the laptop via the USB cable, the EUT is recharged by the laptop.
TC02	<u>The SD Card Test mode</u> The EUT configuration of the emission tests is EUT + SD Card + laptop + USB Cable + Artificial load. During the measurement, the EUT is connected with the laptop via the USB cable, the laptop and the SD card (which is in the EUT) via USB cable for data transmission. The EUT is discharged for the artificial load.
TC03	<u>The Idle Test mode</u> The EUT configuration of the emission tests is EUT During the measurement, the EUT only working in the idle mode.

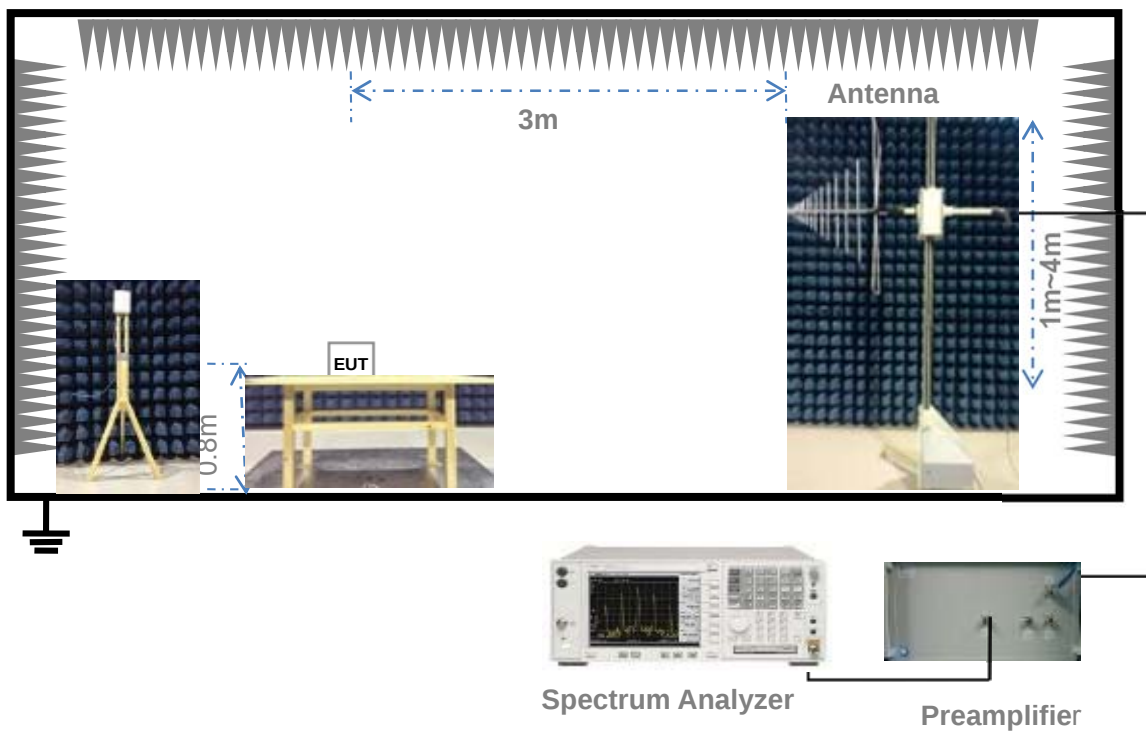
A.16 Test Setups

Test Setup 1



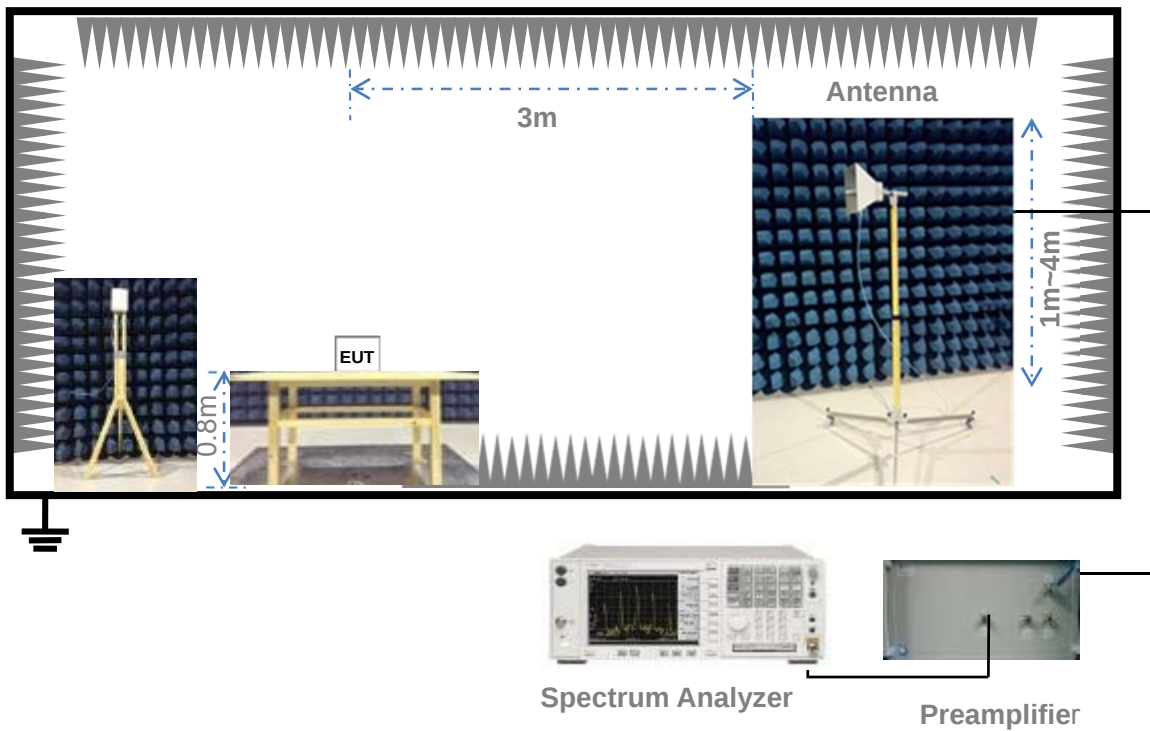
For Radiated Emission Test (Below 30MHz)

Test Setup 2



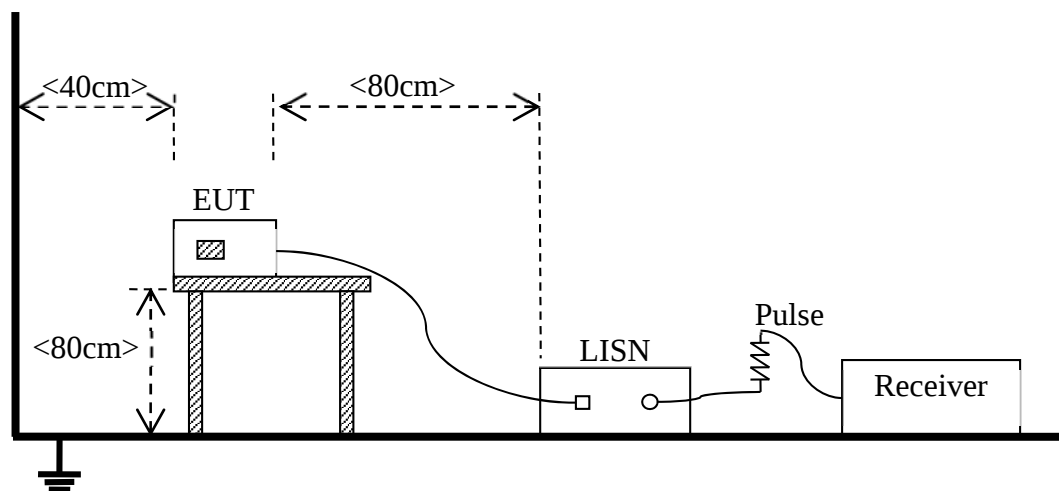
(For Radiated Emission Test (30MHz-1GHz))

Test Setup 3



(For Radiated Emission Test (above 1GHz))

Test Setup 4



(For Conducted Emission, AC Ports Test)

A.17 Test Conditions

Test Case	Test Conditions	
Radiated Emission	Test Env.	NTNV
	Test Setup	Test Setup 2&3
	Test Configuration	TC01~TC03 ^{Note}
Conducted Emission, AC Ports(PC port)	Test Env.	NTNV
	Test Setup	Test Setup 4
	Test Configuration	TC01-TC02 ^{Note}

Note: Based on client request, all normal using modes of the normal function were tested but only the worst test data of the worst mode is reported by this report. The SD card test mode is the worst test in all the test items in this report.

5 TEST ITEMS

A.18 Emission Tests

5.1.1 Radiated Emission

5.1.1.1 Limit

Frequency (MHz)	Field Strength ($\mu\text{V/m}$)	Measurement Distance (m)
0.009 - 0.490	2400/F(kHz)	300
0.490 - 1.705	24000/F(kHz)	30
1.705 - 30.0	30	30
30 - 88	100	3
88 - 216	150	3
216 - 960	200	3
Above 960	500	3

NOTE:

- 1) Field Strength (dB $\mu\text{V/m}$) = 20*log [Field Strength ($\mu\text{V/m}$)].
- 2) In the emission tables above, the tighter limit applies at the band edges.
- 3) For above 1000MHz, limit field strength of harmonics: 54dB $\mu\text{V/m}$ @3m (AV) and 74dB $\mu\text{V/m}$ @3m (PK)

5.1.1.2 Test Procedure

All Spurious Emission tests were performed in X, Y, Z axis direction. And only the worst axis test condition was recorded in this test report.

An initial pre-scan was performed in the chamber using the EMI Receiver in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by Bi-Log antenna with 2 orthogonal polarities.

5.1.2 Conducted Emission

5.1.2.1 Test Limit

Frequency range (MHz)	Conducted Limit (dB μ V)	
	Quasi-peak	Average
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5 - 30	60	50

NOTE:

- 1) The limit is applicable to Class B ITE.
- 2) The lower limit shall apply at the band edges.
- 3) The limit decreases linearly with the logarithm of the frequency in the range 0.15 - 0.50MHz.

5.1.2.2 Test Procedure

The EUT is connected to the power mains through a LISN which provides 50 Ω /50 μ H of coupling impedance for the measuring instrument. The test frequency range is from 150 kHz to 30MHz. The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels that are more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed.

ANNEX A TEST RESULTS

A.19 Radiated Emission

Note 1: The symbol of “--” in the table which means not application.

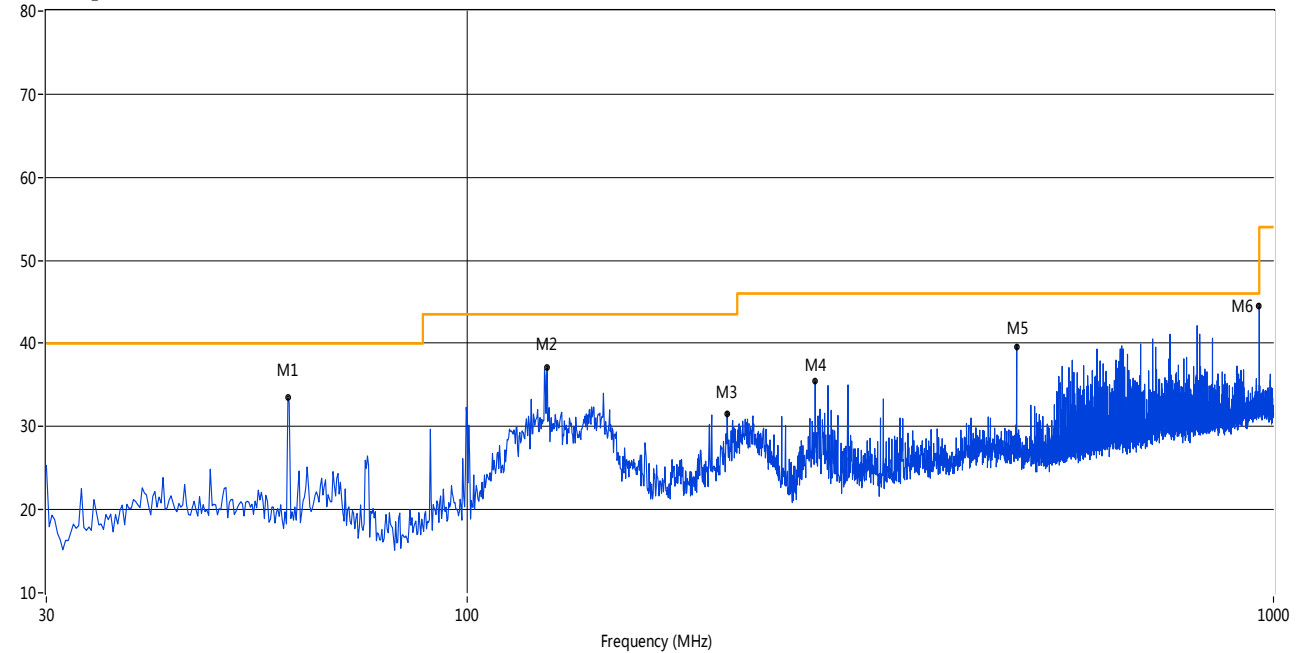
Note 2: For the test data above 1GHz, According the ANSI C63.4-2014, where limits are specified for both average and peak (or quasi-peak) detector functions, if the peak (or quasi-peak) measured value complies with the average limit, it is unnecessary to perform an average measurement.

Test Data and Plots (SD card test mode)

The low frequency, which started from 9 kHz to 30MHz, was pre-scanned and the result which was 20dB lower than the limit line per 15.31(o) was not reported.

A.1.1 Test Antenna Vertical, 30MHz – 1GHz

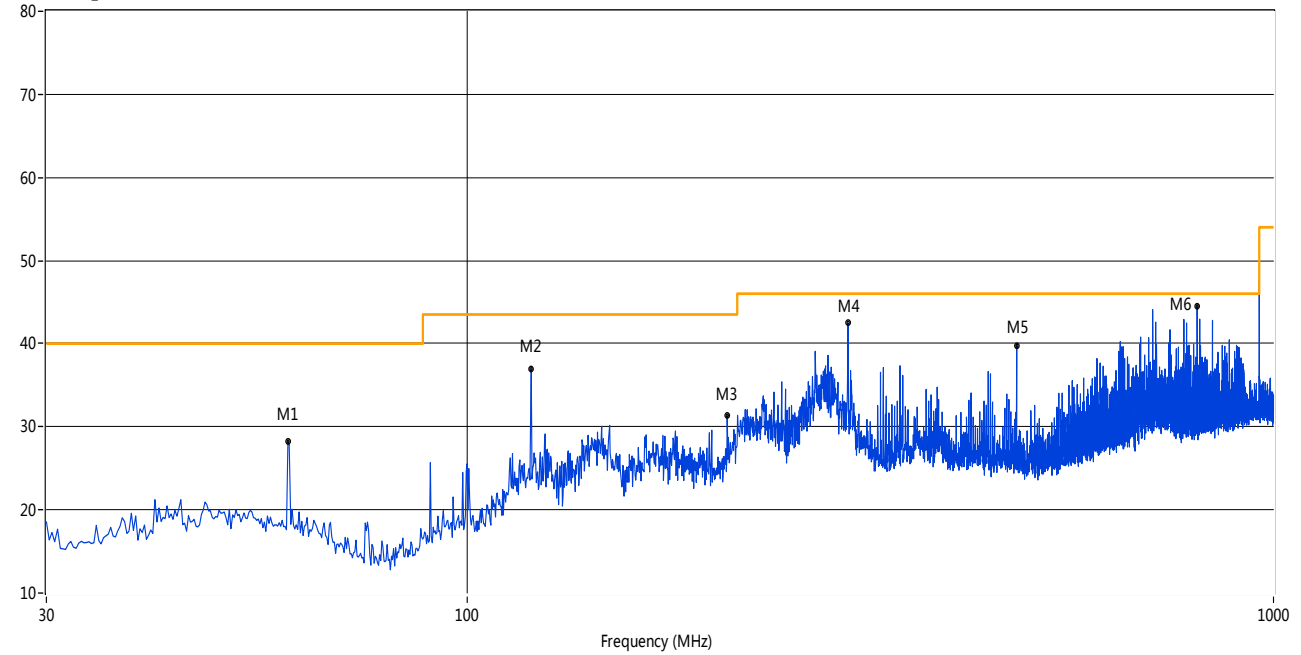
RE Test case_FCC 15B 30MHz-1GHz



Frequency (MHz)	Peak Level (dBuV/m)	Q-peak Level (dBuV/m)	Average Level (dBuV/m)	Factor (dB)	PK Limit (dBuV/m)	QP Limit (dBuV/m)	AV Limit (dBuV/m)	Margin (dB)	Table (o)	Height (cm)	ANT	Verdict
59.82	31.92	--	--	-20.02	--	40.0	--	8.08	88.40	100	Vertical	PASS
125.52	37.10	--	--	-22.74	--	43.5	--	6.40	6.50	100	Vertical	PASS
209.89	31.40	--	--	-20.22	--	43.5	--	12.10	321.10	100	Vertical	PASS
270.01	35.43	--	--	-18.59	--	46.0	--	10.57	0.70	100	Vertical	PASS
479.97	39.76	--	--	-14.05	--	46.0	--	6.24	271.00	100	Vertical	PASS
960.00	44.54	43.36	--	-5.36	--	46.0	--	2.64	344.10	100	Vertical	PASS

A.1.2 Test Antenna Horizontal, 30MHz – 1GHz

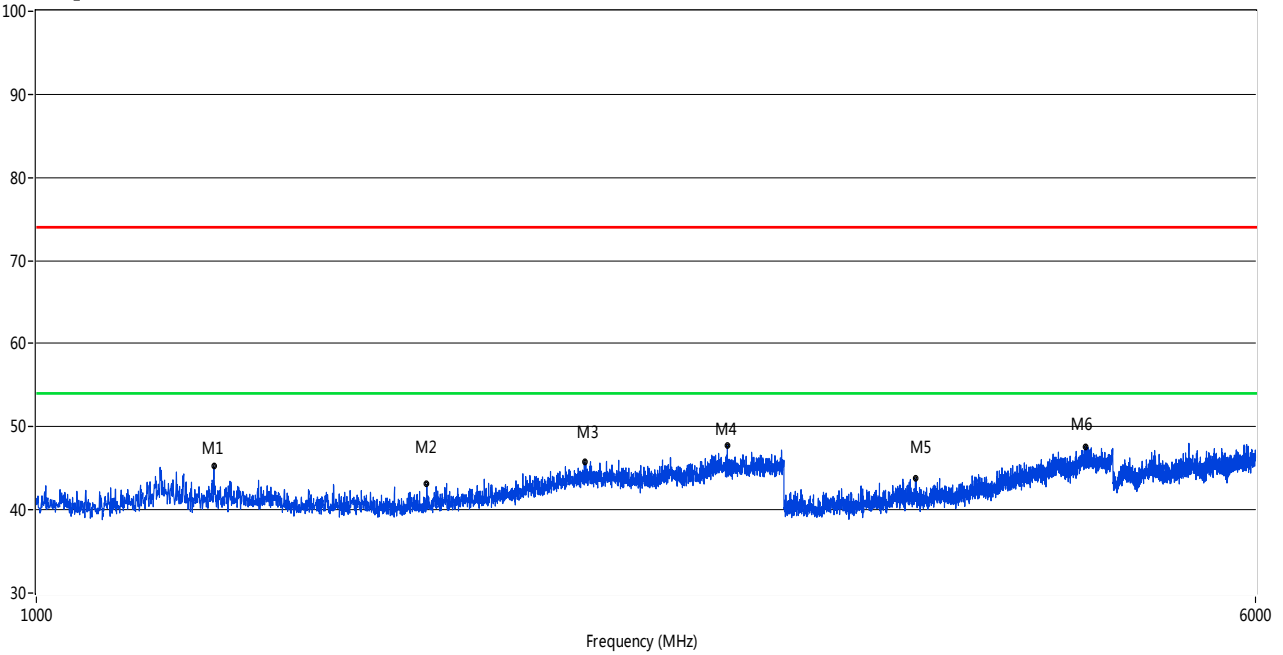
RE Test case_FCC 15B 30MHz-1GHz



Frequency (MHz)	Peak Level (dBuV/m)	Q-peak Level (dBuV/m)	Average Level (dBuV/m)	Factor (dB)	PK Limit (dBuV/m)	QP Limit (dBuV/m)	AV Limit (dBuV/m)	Margin (dB)	Table (o)	Height (cm)	ANT	Verdict
59.82	31.92	--	--	-20.02	--	40.0	--	8.08	88.40	100	Horizontal	PASS
119.94	36.92	--	--	-21.90	--	43.5	--	6.58	198.60	100	Horizontal	PASS
209.89	31.40	--	--	-20.22	--	43.5	--	12.10	321.10	100	Horizontal	PASS
296.44	42.49	--	--	-17.89	--	46.0	--	3.51	92.90	100	Horizontal	PASS
479.97	39.76	--	--	-14.05	--	46.0	--	6.24	271.00	100	Horizontal	PASS
803.87	44.58	43.61	--	-7.52	--	46.0	--	2.39	53.60	100	Horizontal	PASS

A.1.3 Test Antenna Vertical, 1GHz – 6GHz

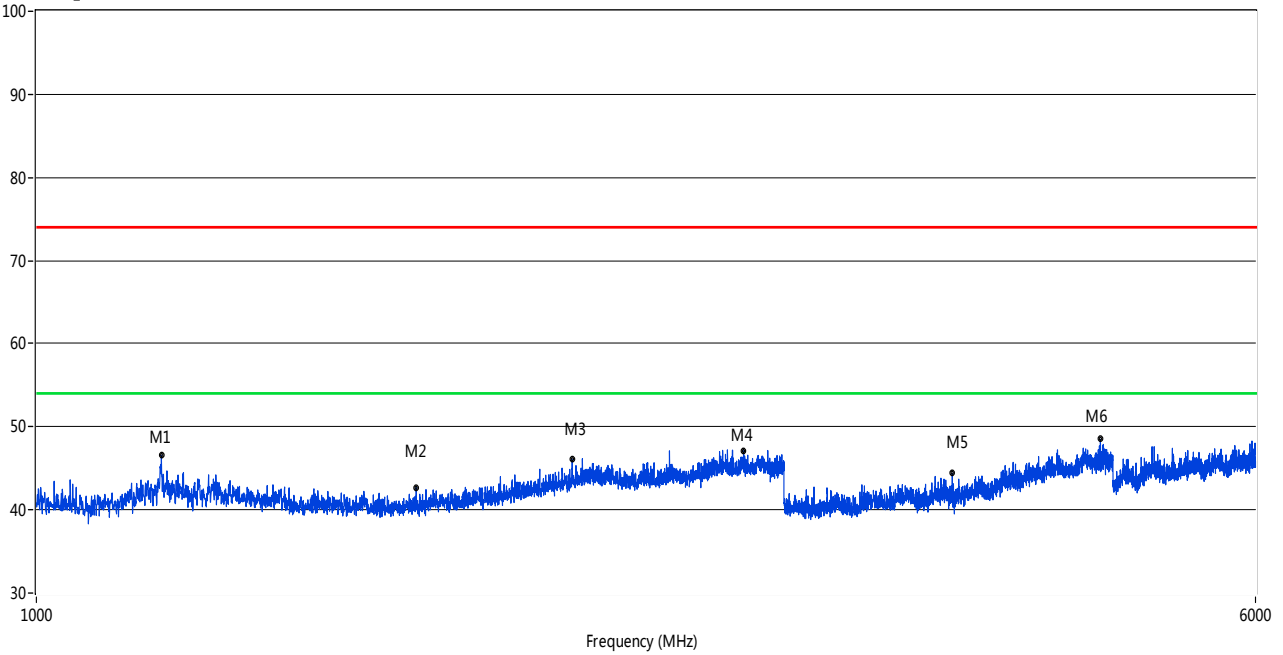
RE Test case_FCC 15B 1GHz-6GHz



Frequency (MHz)	Peak Level (dBuV/m)	Q-peak Level (dBuV/m)	Average Level (dBuV/m)	Factor (dB)	PK Limit (dBuV/m)	QP Limit (dBuV/m)	AV Limit (dBuV/m)	Margin (dB)	Table (o)	Height (cm)	ANT	Verdict
1297.93	45.21	--	--	-5.05	74.0	--	54.0	8.79	14.60	100	Vertical	PASS
1775.31	43.10	--	--	-3.88	74.0	--	54.0	10.90	359.40	100	Vertical	PASS
2237.69	45.76	--	--	-0.99	74.0	--	54.0	8.24	94.30	100	Vertical	PASS
2761.06	47.72	--	--	1.48	74.0	--	54.0	6.28	0.60	100	Vertical	PASS
3639.59	43.78	--	--	9.66	74.0	--	54.0	10.22	267.40	100	Vertical	PASS
4672.08	47.65	--	--	12.71	74.0	--	54.0	6.35	326.30	100	Vertical	PASS

A.1.4 Test Antenna Horizontal, 1GHz – 6GHz

RE Test case_FCC 15B 1GHz-6GHz



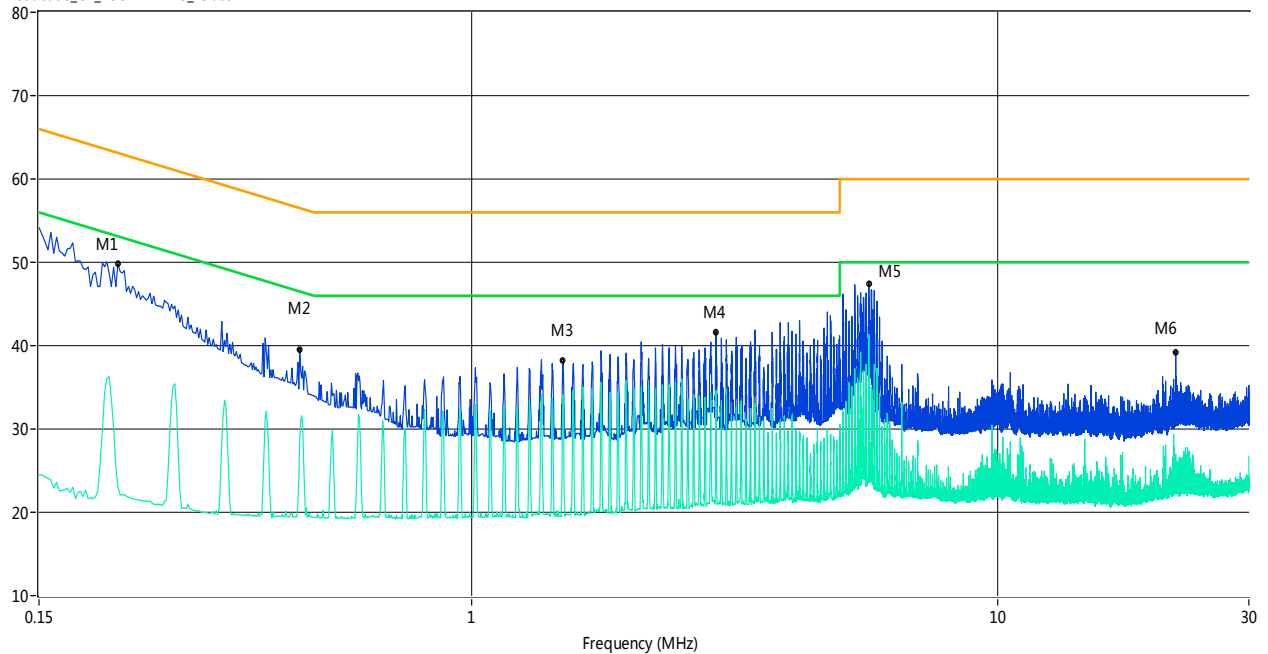
Frequency (MHz)	Peak Level (dBuV/m)	Q-peak Level (dBuV/m)	Average Level (dBuV/m)	Factor (dB)	PK Limit (dBuV/m)	QP Limit (dBuV/m)	AV Limit (dBuV/m)	Margin (dB)	Table (o)	Height (cm)	ANT	Verdict
1201.95	46.54	--	--	-5.37	74.0	--	54.0	7.46	284.40	100	Horizontal	PASS
1747.81	42.73	--	--	-4.36	74.0	--	54.0	11.27	109.40	100	Horizontal	PASS
2197.70	46.05	--	--	-1.08	74.0	--	54.0	7.95	300.30	100	Horizontal	PASS
2827.54	47.09	--	--	1.57	74.0	--	54.0	6.91	173.20	100	Horizontal	PASS
3842.04	44.39	--	--	10.27	74.0	--	54.0	9.61	247.00	100	Horizontal	PASS
4777.06	48.49	--	--	13.26	74.0	--	54.0	5.51	360.00	100	Horizontal	PASS

A.20 Conducted Emission

Test Data and Plots (SD card test mode)

A.2.1 L Phase

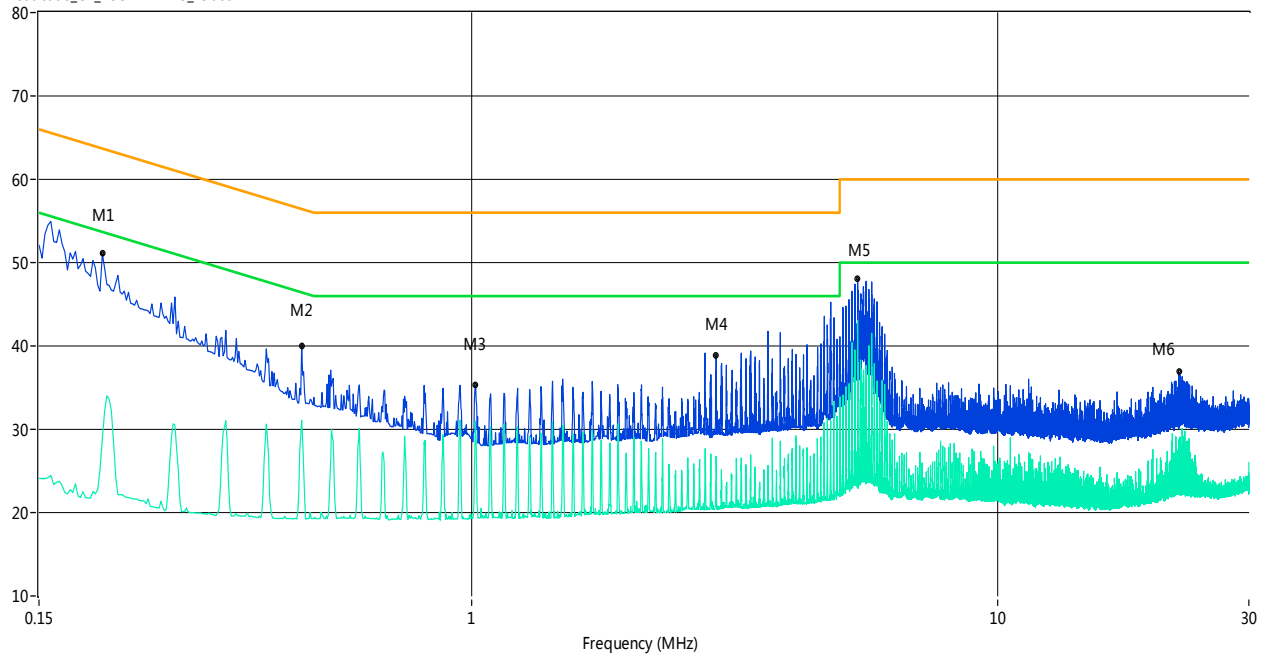
CE Test case_CE_FCC PART 15_ Class B



Frequency (MHz)	Peak Level (dBuV)	Q-peak Level (dBuV)	Average Level (dBuV)	Factor (dB)	QP Limit (dBuV)	AV Limit (dBuV)	Margin (dB)	Line	Verdict
0.21	49.8	--	23.0	13.00	64.2	54.2	31.20	L Line	PASS
0.47	39.5	--	28.8	13.00	56.9	46.9	18.10	L Line	PASS
1.49	38.2	--	34.1	13.00	56.0	46.0	11.90	L Line	PASS
2.91	41.7	--	34.6	13.00	56.0	46.0	11.40	L Line	PASS
5.68	47.4	--	41.3	13.00	60.0	50.0	8.70	L Line	PASS
21.79	39.2	--	27.0	13.00	60.0	50.0	23.00	L Line	PASS

A.2.2 N Phase

CE Test case_CE_FCC PART 15_ Class B



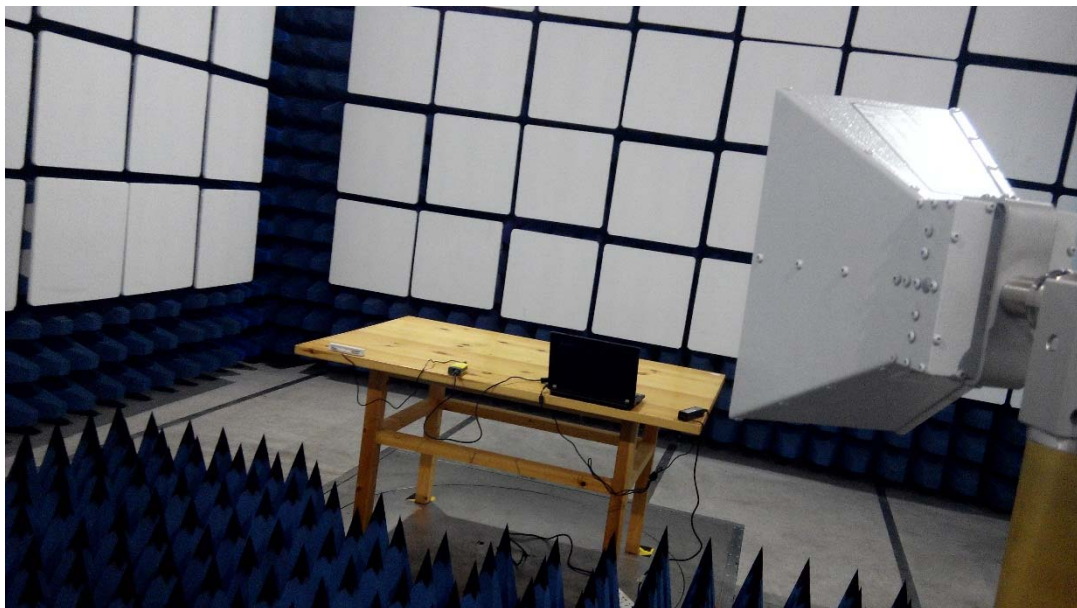
Frequency (MHz)	Peak Level (dBuV)	Q-peak Level (dBuV)	Average Level (dBuV)	Factor (dB)	QP Limit (dBuV)	AV Limit (dBuV)	Margin (dB)	Line	Verdict
0.20	51.1	--	29.0	13.00	64.6	54.6	25.60	N Line	PASS
0.47	40.1	--	31.1	13.00	56.7	46.7	15.60	N Line	PASS
1.02	35.3	--	29.9	13.00	56.0	46.0	16.10	N Line	PASS
2.91	38.9	--	26.8	13.00	56.0	46.0	19.20	N Line	PASS
5.41	48.0	--	43.0	13.00	60.0	50.0	7.00	N Line	PASS
22.07	36.9	--	26.2	13.00	60.0	50.0	23.80	N Line	PASS

ANNEX B TEST SETUP PHOTOS

B.1 Radiated Field Strength Measurement

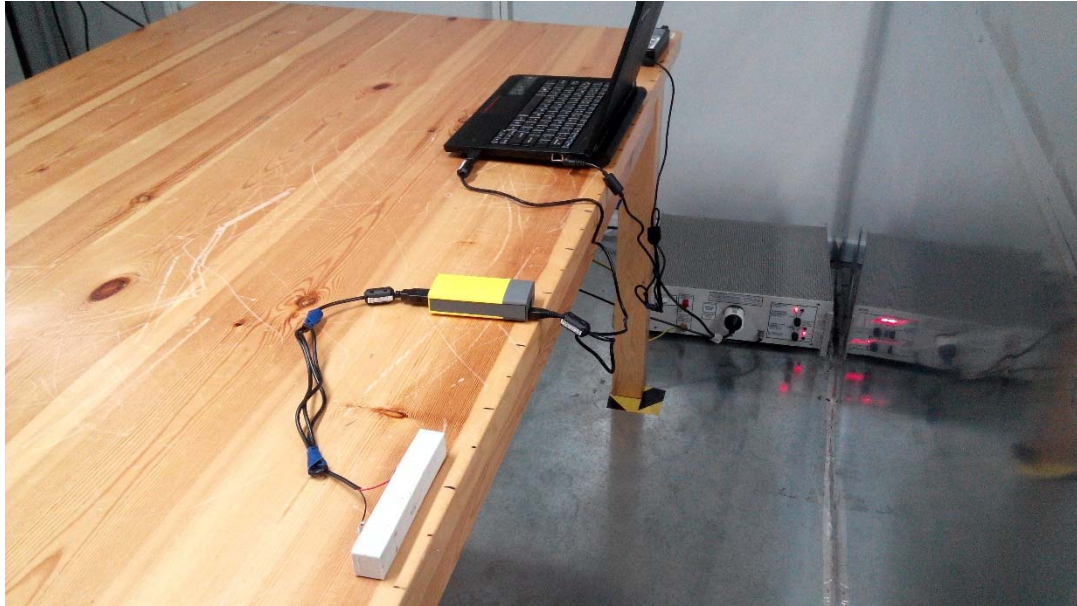


30MHz~1GHz SD Card Test Mode



1GHz~6GHz SD Card Test Mode

B.2 Conducted Emission



SD Card Test Mode

ANNEX C EUT PHOTOS

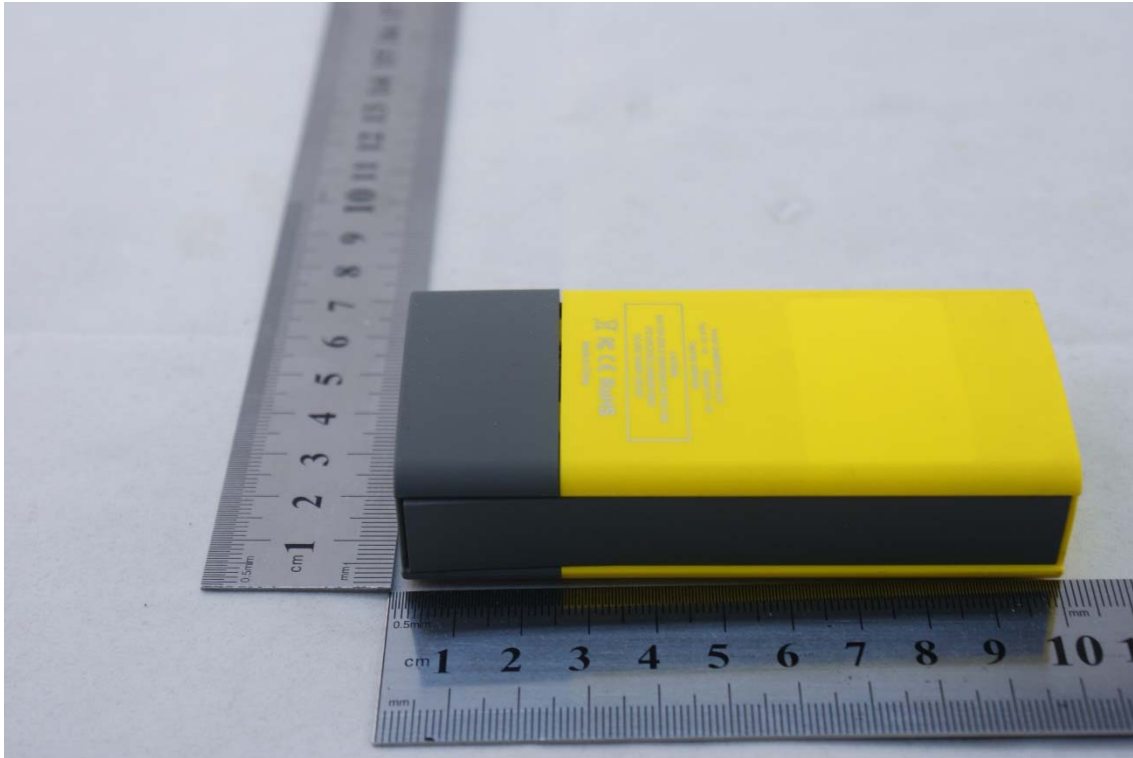
C.1 Appearance of the EUT



THE FRONT OF EUT



THE BACK OF EUT



THE LEFT OF EUT



THE RIGHT OF EUT

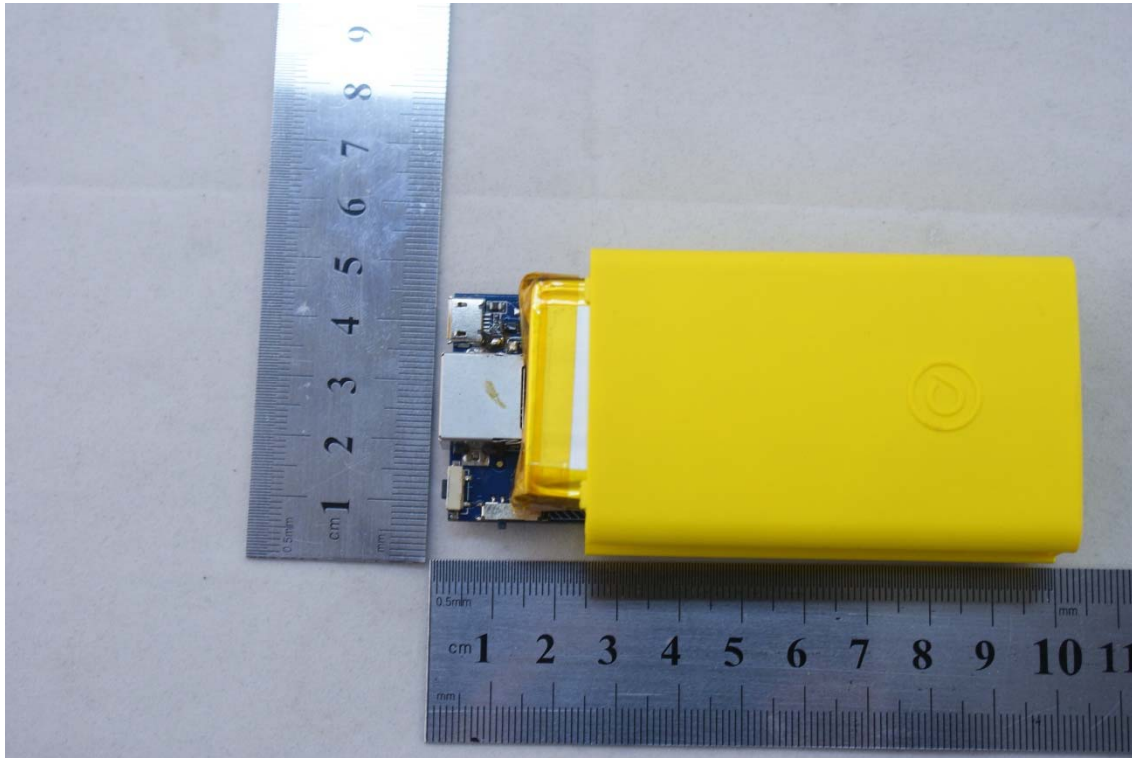


THE UP OF EUT



THE DOWN OF EUT

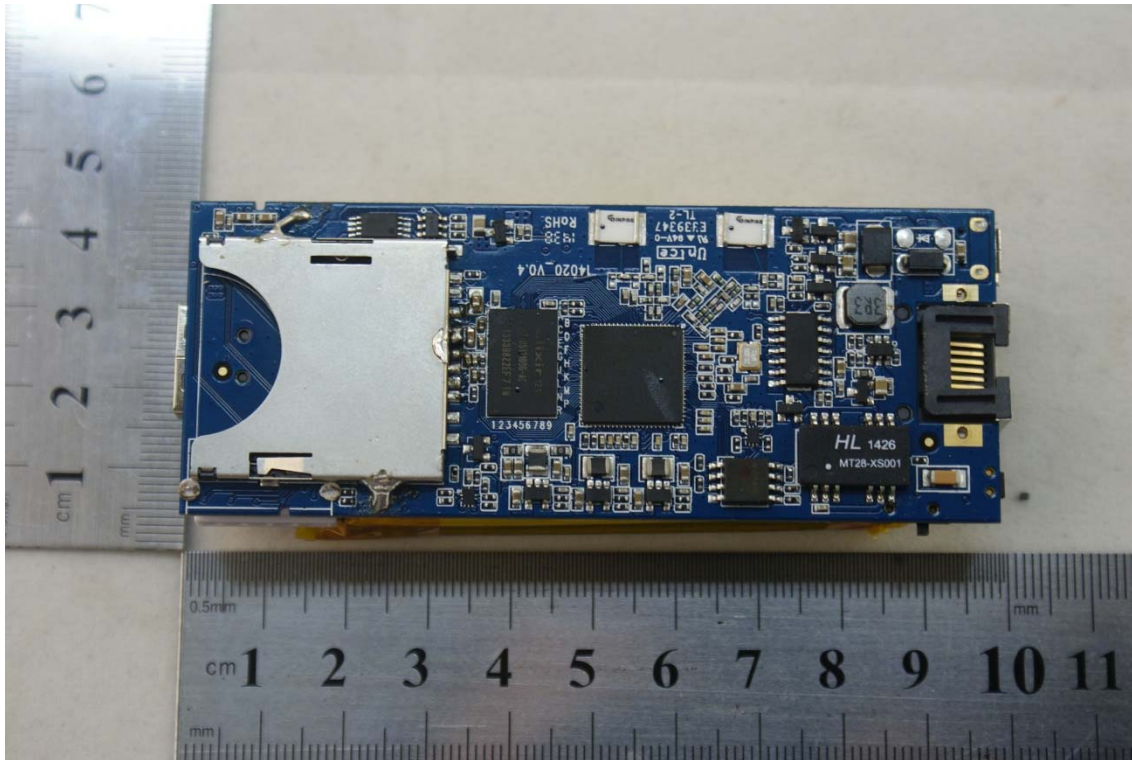
C.2 Inside of the EUT



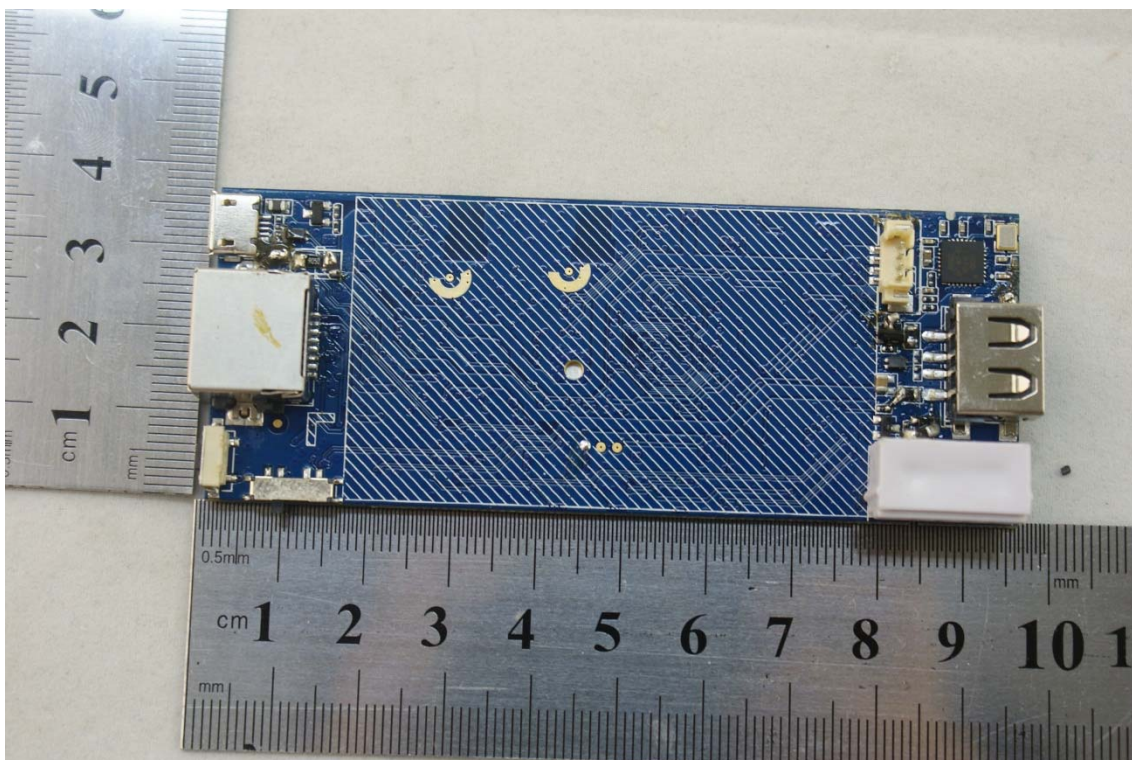
EUT UNCOVER TOP VIEW 1



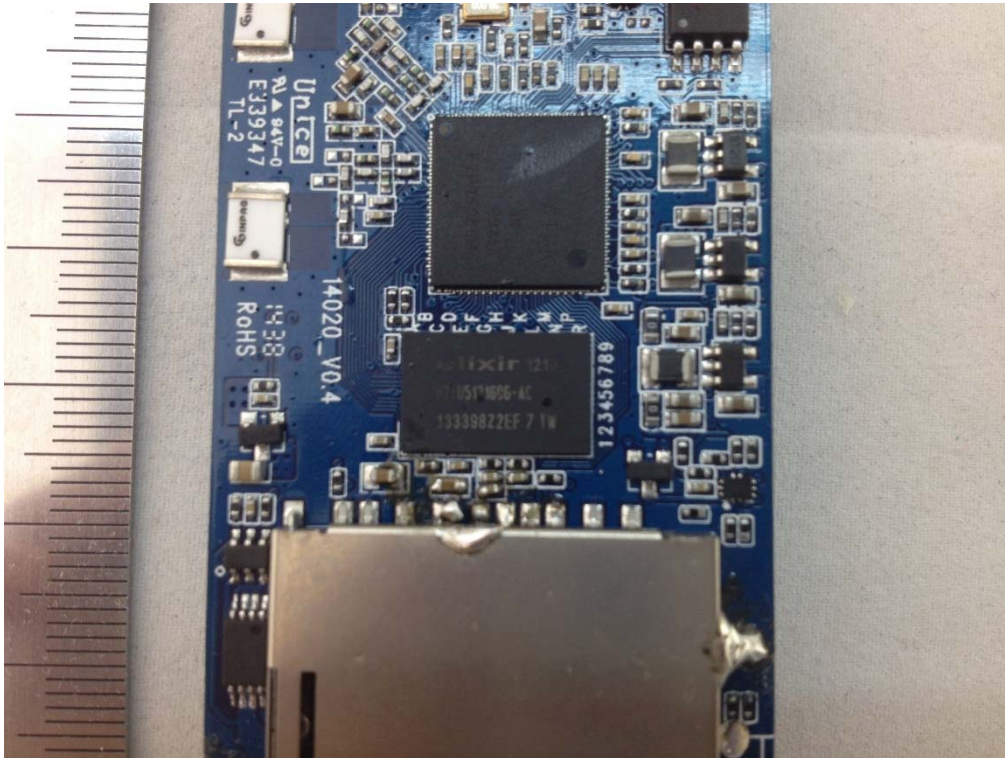
EUT UNCOVER TOP VIEW 2



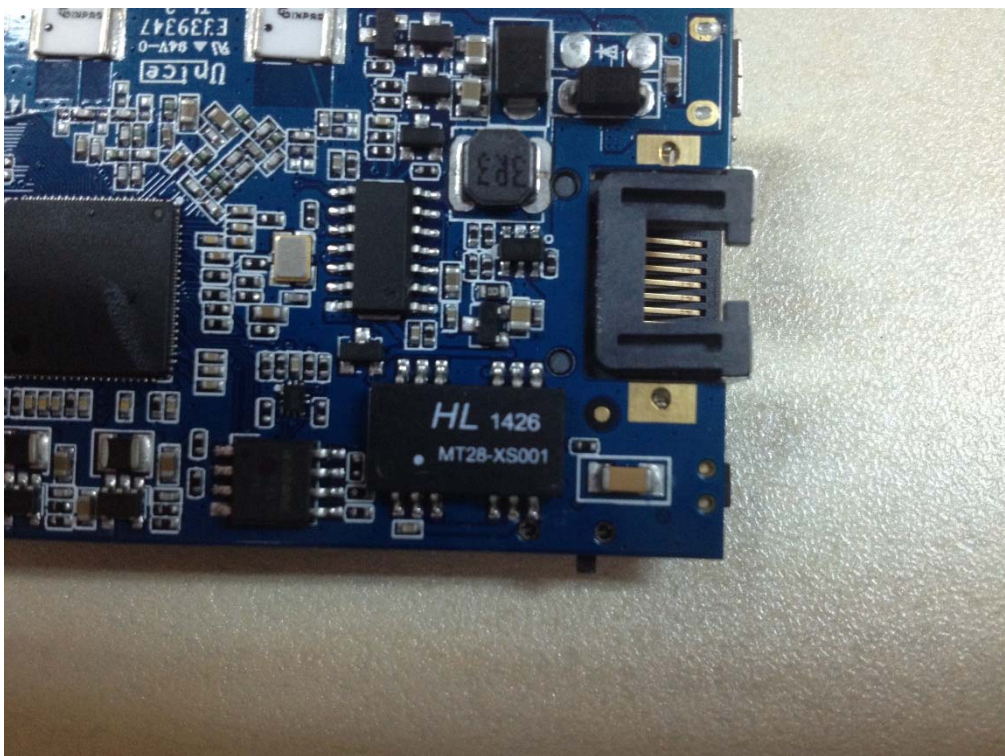
MAIN BOARD TOP VIEW 1



MAIN BOARD BACK VIEW 1



MAIN BOARD TOP VIEW 2



MAIN BOARD TOP VIEW 3



BATTERY

--END OF REPORT--